## Notice of References Cited

Application/Control No. 10/594,997		Applicant(s)/Patent Under Reexamination ITOH ET AL.		
Examiner	Art Unit			
HENRY S. HU	1764	Page 1 of 1		

## U.S. PATENT DOCUMENTS

	U.S. I ATENT DOCUMENTS				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,038,004 B2	05-2006	Chen et al.	528/86
*	В	US-5,114,809	05-1992	Nakacho et al.	429/315
	С	US-			
	D	US-			
	Е	US-			
	F	US-		-	
	G	US-		-	
	Н	US-		-	
	_	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	CN-1385464 A	12-2002	CN	Cui, Wei	
*	0	JP-2004-087137	03-2004	JP	Kamiyama, Koji	
*	Р	WO-02-92638 A1	11-2002	wo	Cui, Wei	
*	Q	CN-2005-80012249.3	02-2009	CN	Itoh et al.	
*	R	KR-2008-003475317	01-2008	KR	(Korean abstract only)	
	s					
	Т					

## MONI DATENT DOCUMENTS

	NON-PATENT DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	v			
	w			
	х			

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